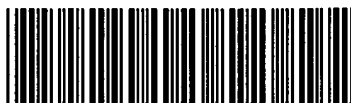


Search Notes

Application/Control No.

10/563,030

Examiner

Muhammad Akbar

Applicant(s)/Patent under
Reexamination

STEFFEN ET AL.

Art Unit

2618

SEARCHED

Class	Subclass	Date	Examiner
455	67.11	3/12/2007	MA
455	423	3/13/2007	MA

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Words searches in EAST using class 455 subclass 67.11,423	3/12/2007	MA
WIPO/ECS/IEEE documents searches by using keywords high frequency measuring device with DUT	3/13/2007	MA
Words searches by using WWW with keywords high frequency measuring device with DUT	3/15/07	MA